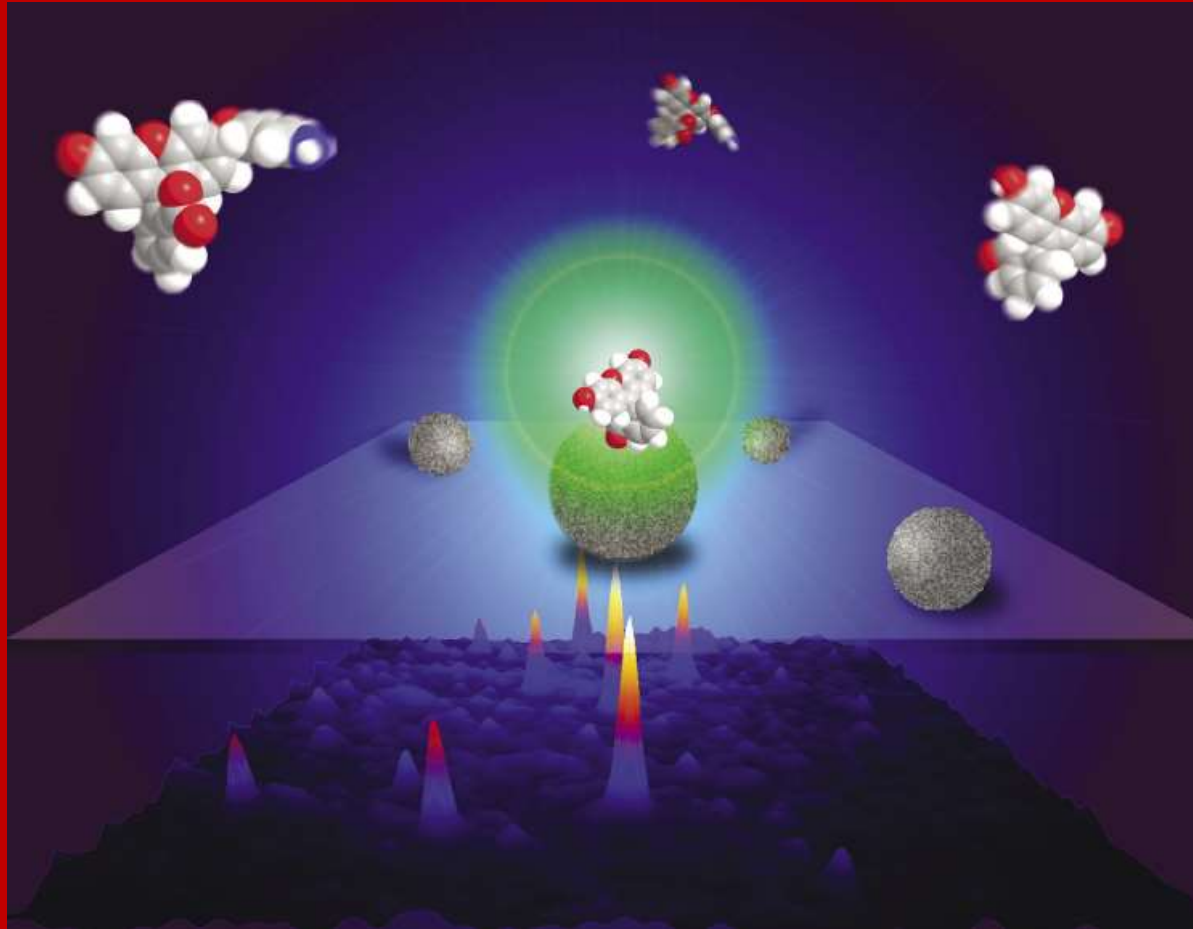


# Catalysis

## Characterization of Catalysts



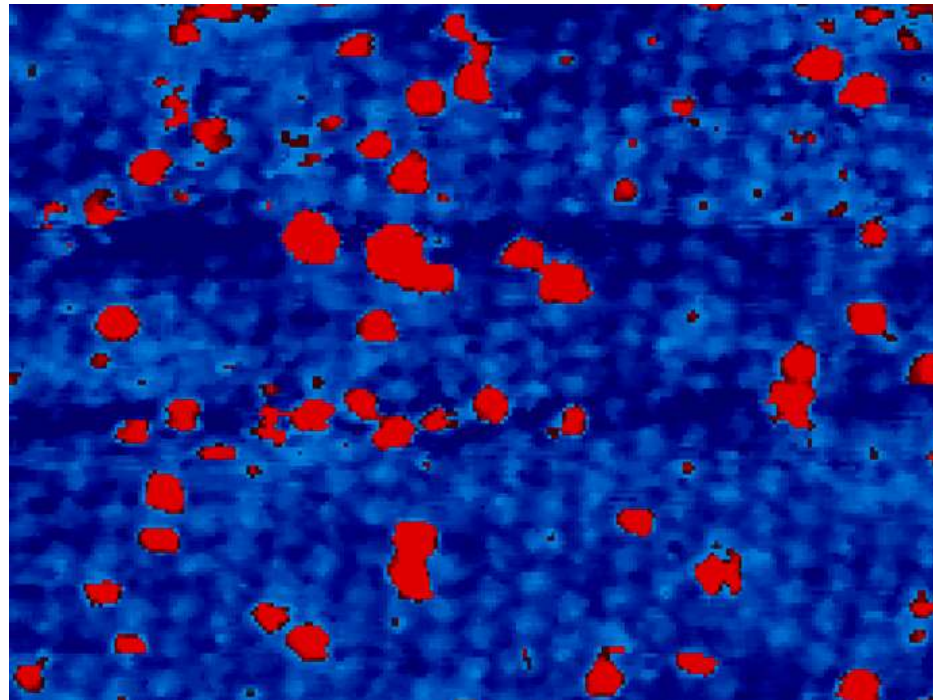
**Dr. Hans Elemans**  
J.Elemans@science.ru.nl

# Importance

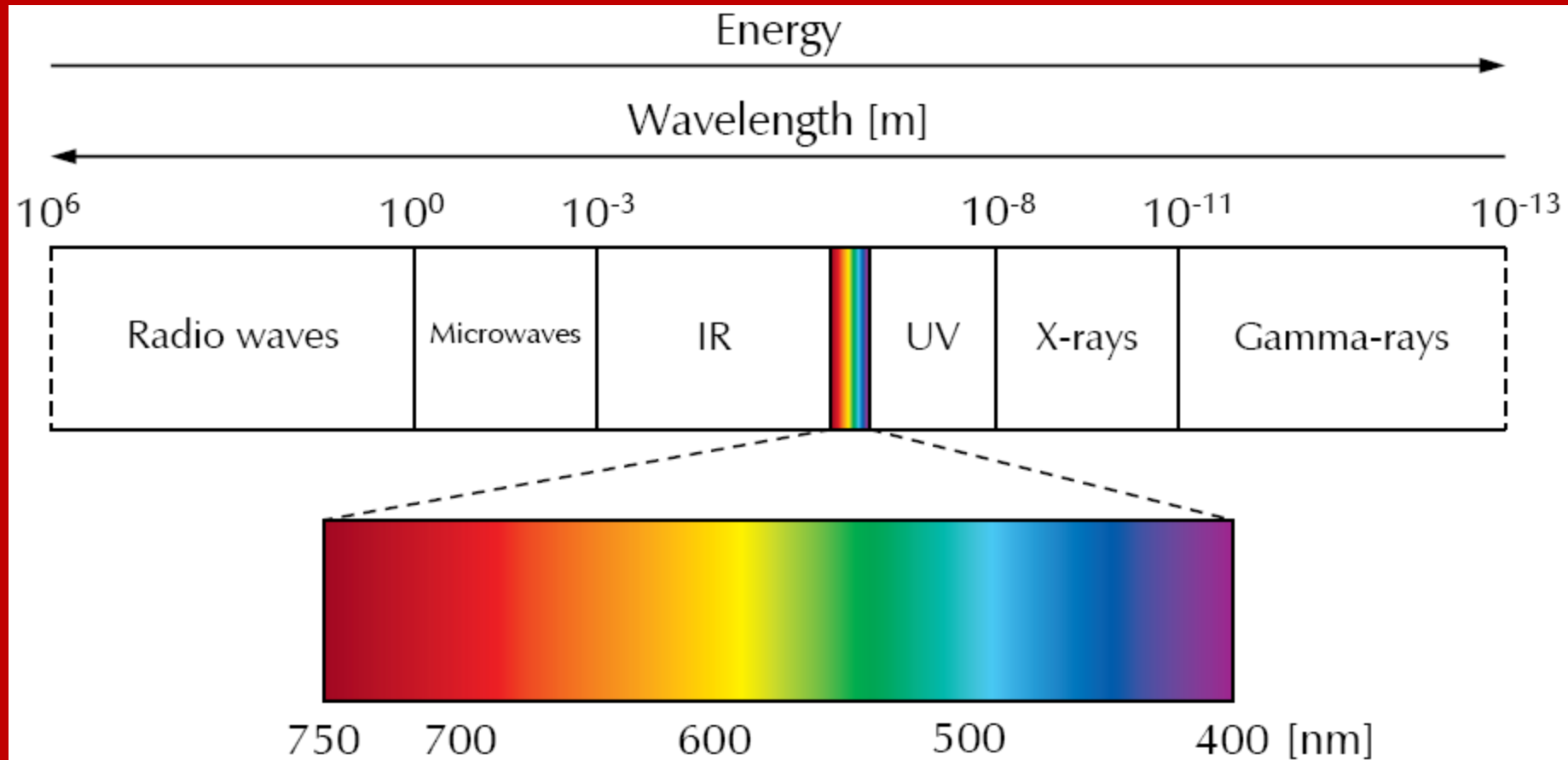
## Establish in detail the structure-activity relationships of catalysts

- Stability, (local) activity, selectivity, regenerability
- *In situ*: under reaction conditions at highest detail possible
- *In operando*: at the moment the catalytic reaction is going on

**Goals: understand precisely how catalysts work → design & development of better catalysts (→ €€€)**



# Spectroscopic Characterization



# Spectroscopic techniques

## Spectroscopic characterization in solution

- Nuclear Magnetic Resonance (NMR)
- Electron Paramagnetic Resonance (EPR)
- UV-vis
- Fluorescence
- Infrared (IR)
- Raman

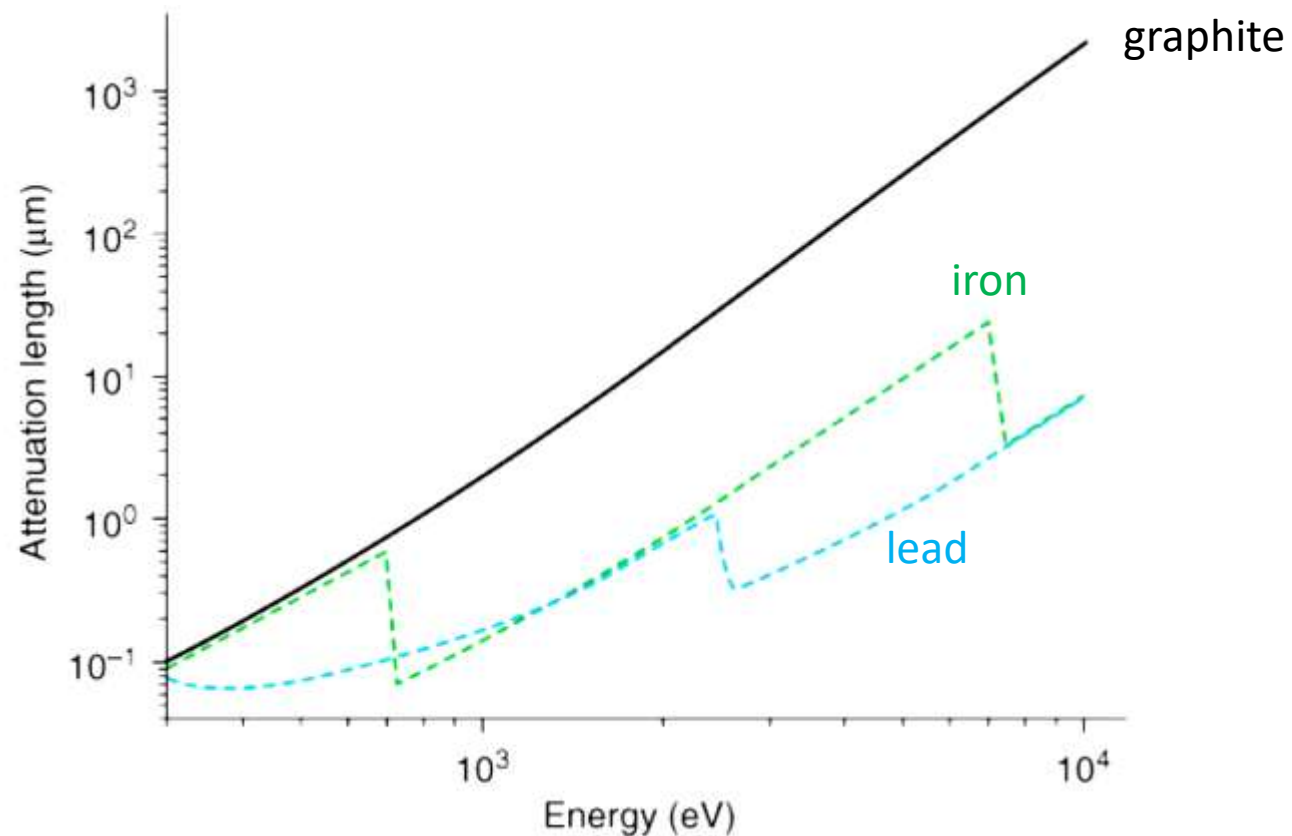
## Spectroscopic characterization in solid state / on surfaces

- NMR, EPR, IR, UV-vis
- X-ray Diffraction (XRD)
- X-ray Absorption (XAS)
- X-ray Scattering
- X-ray Photoelectron Spectroscopy (XPS)

# X-rays

## Electromagnetic radiation with $\lambda < 10 \text{ nm}$ ( $E > 100 \text{ eV}$ )

- Generated by interaction of high energy electrons with a material
- Soft X-rays:  $< 2 \text{ keV}$ . Prefer vacuum and have low penetrating power
- Hard X-rays:  $> 5 \text{ keV}$ . High penetrating power

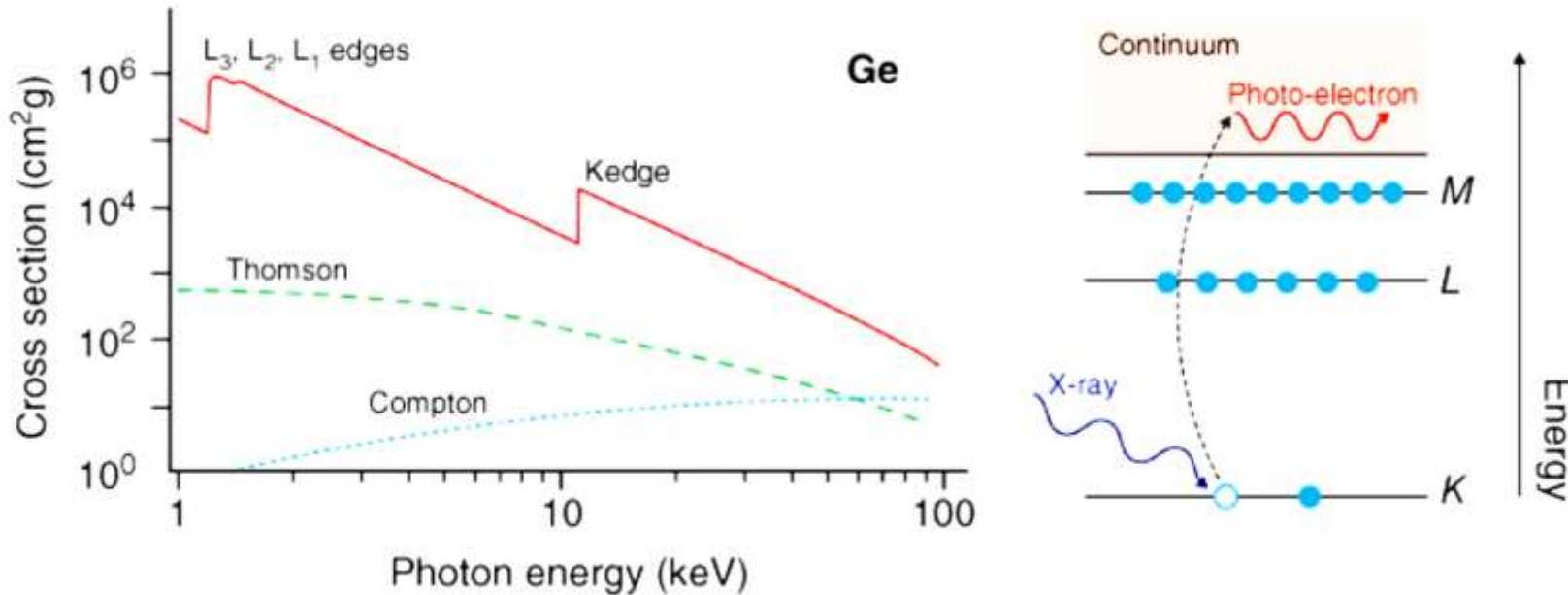


**Attenuation length:** depth at which energy intensity is reduced by  $1/e$  of the starting value

# X-rays

## Types of interactions with matter

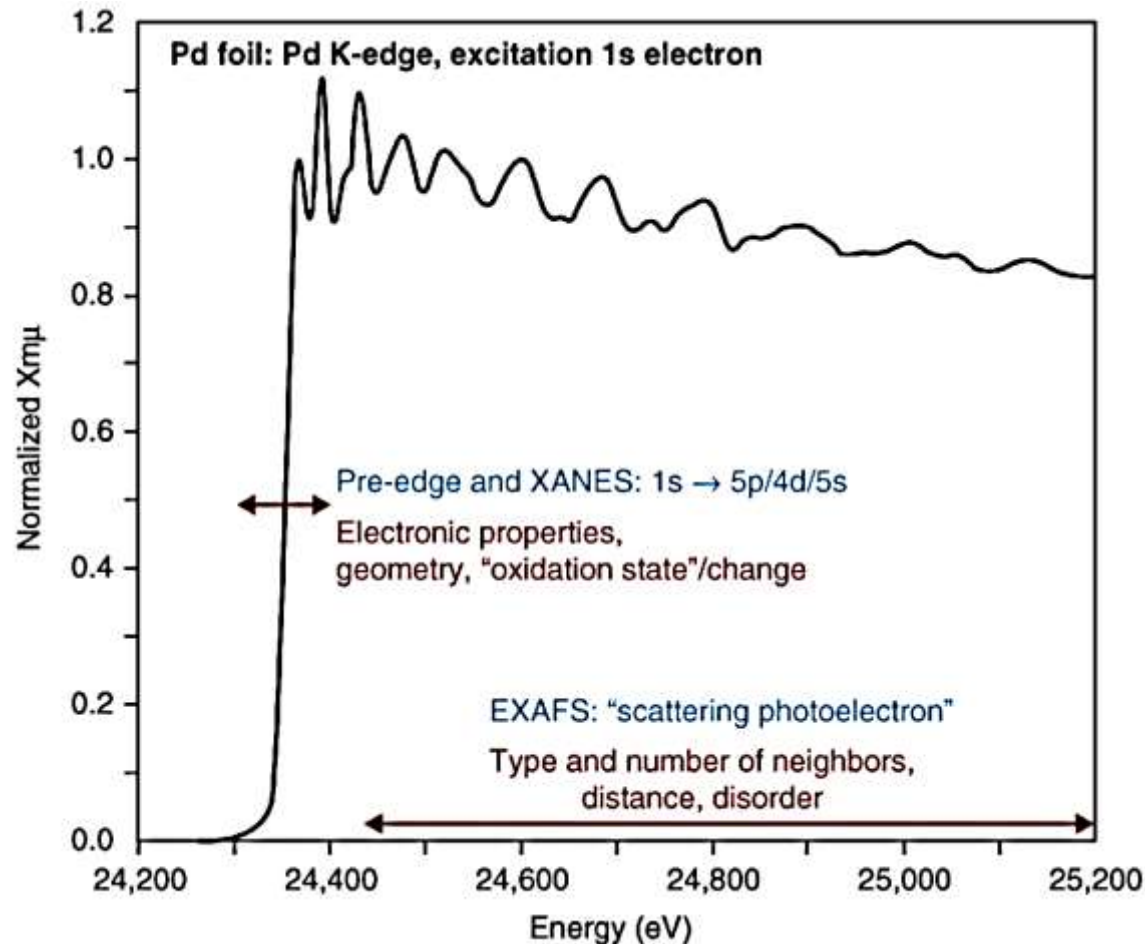
- X-ray photon can be **absorbed** by exciting an electron of an element to an empty state or to the continuum (photoelectric effect). Probing excitation spectrum as function of X-ray energy: [X-ray Absorption Spectroscopy \(XAS\)](#) and [X-ray Photoelectron Spectroscopy \(XPS\)](#)



- X-ray photon can be elastically **scattered** by electrons in a material (Thomson scattering). Techniques: [X-ray diffraction \(XRD\)](#), [Wide-Angle X-ray Scattering \(WAXS\)](#) and [Small-Angle X-ray Scattering \(SAXS\)](#)

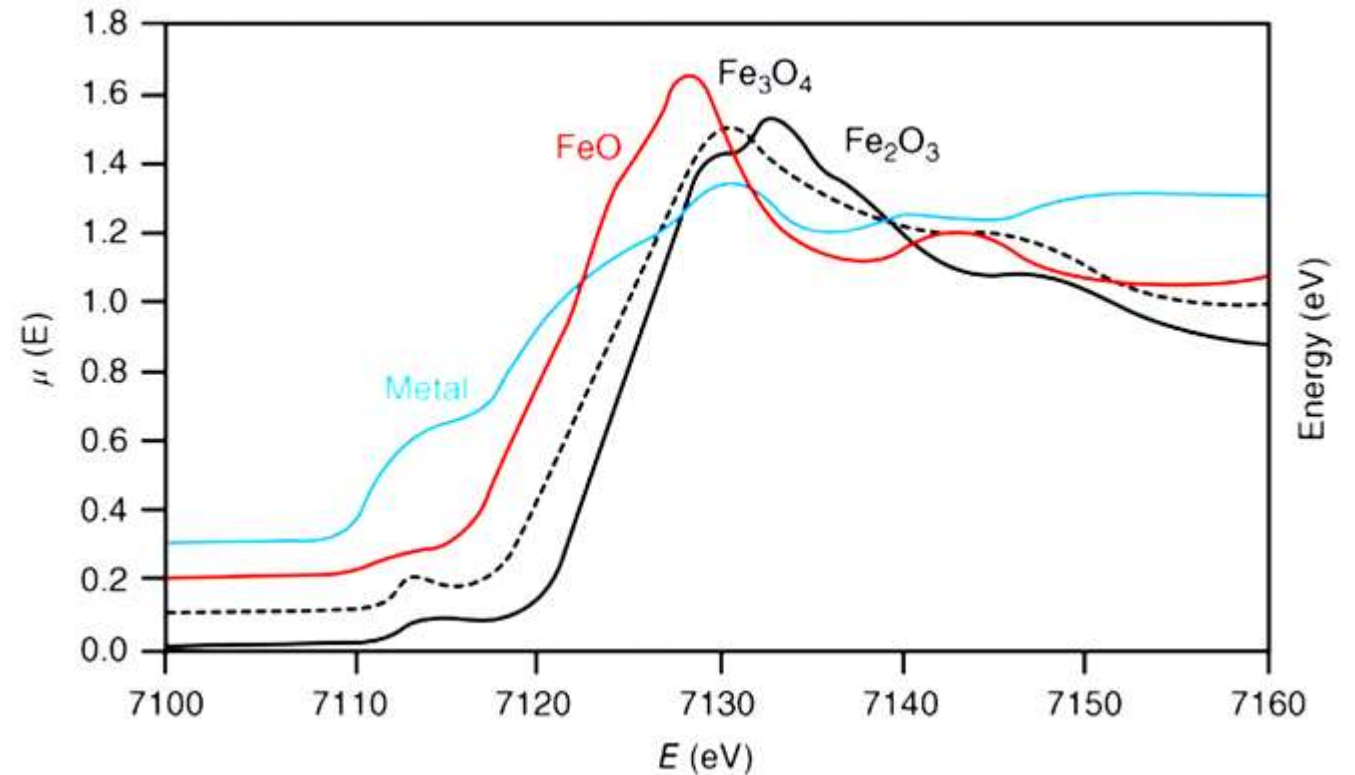
# X-ray absorption spectroscopy (XAS)

- **XANES:** X-ray Absorption Near Edge Structure. Provides direct information on the energy difference between core and excited state
- **EXAFS:** Extended X-ray Absorption Fine Structure. Provides information about the close environment of the excited electron



# XANES

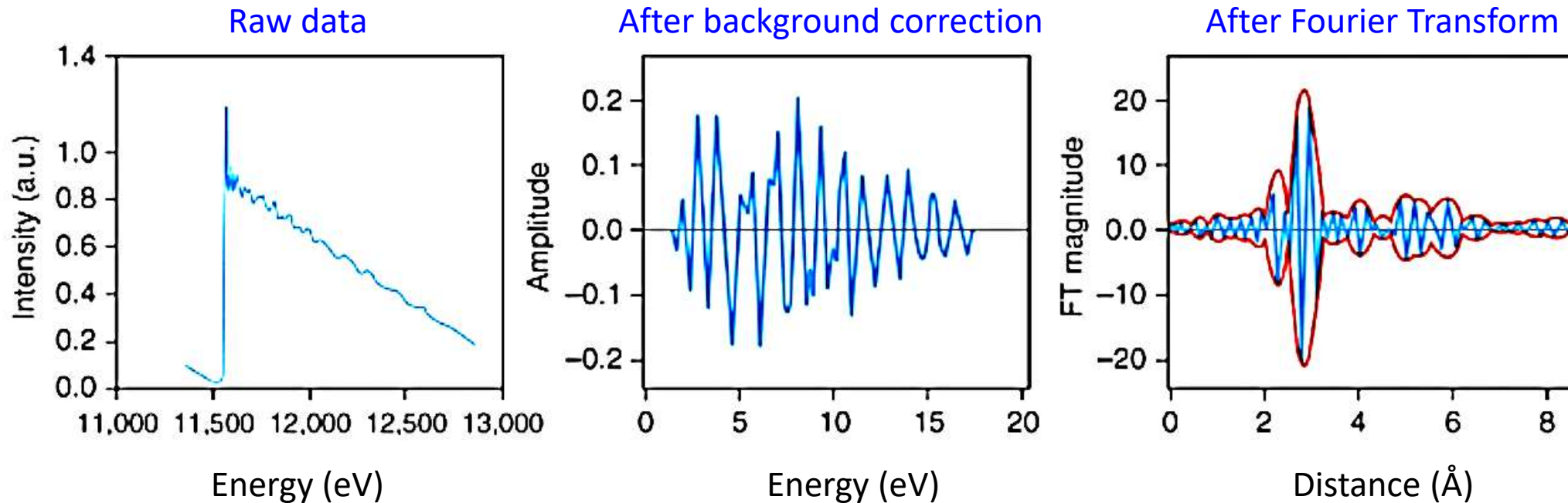
- Information about direct environment of excited electron
- E.g. oxidation state and charge of an element
- Local geometry, e.g. ligands bound to metal
- Quantitative analysis (still) not straightforward; trends may be observed but they become complicated rapidly





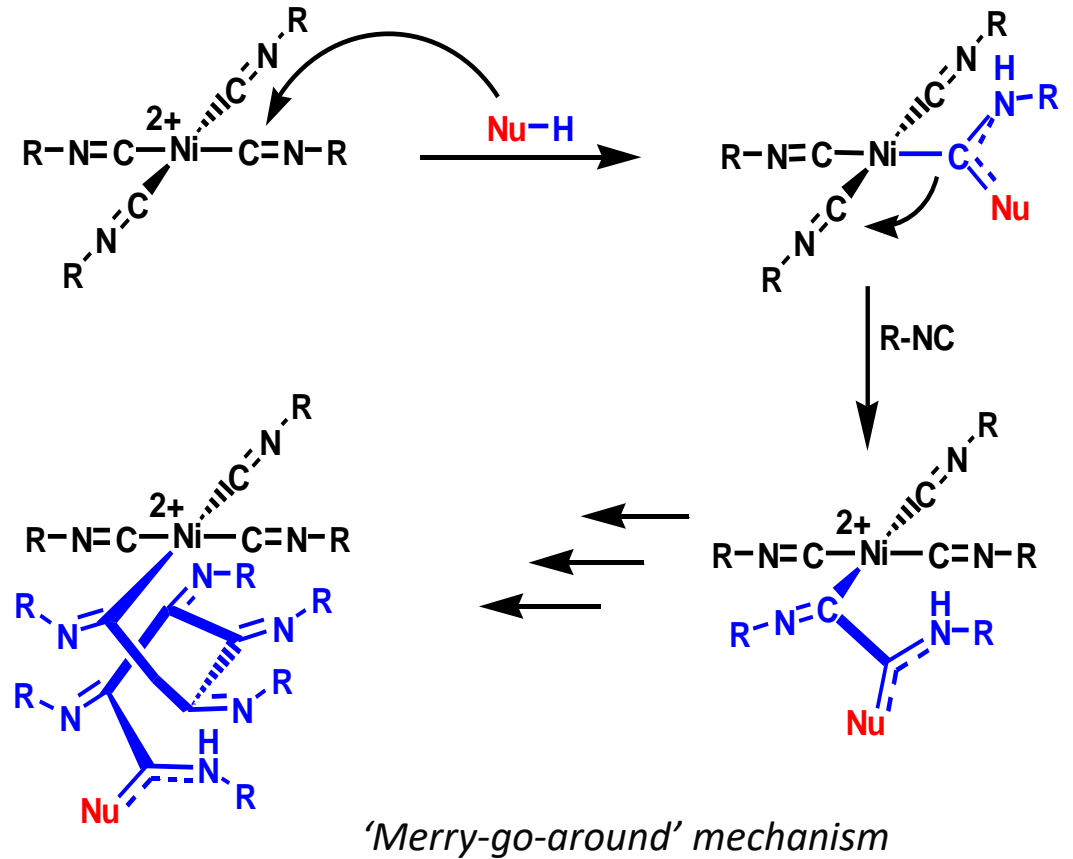
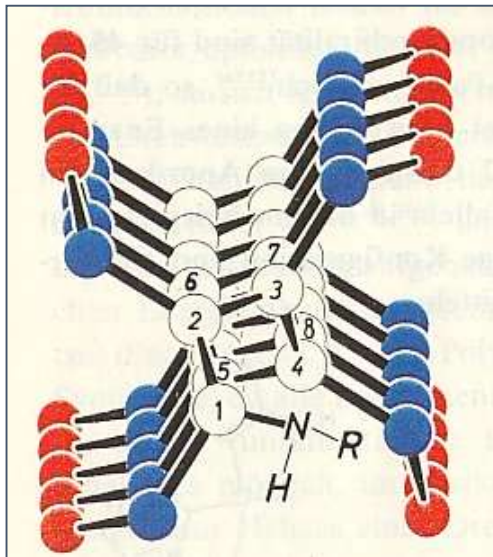
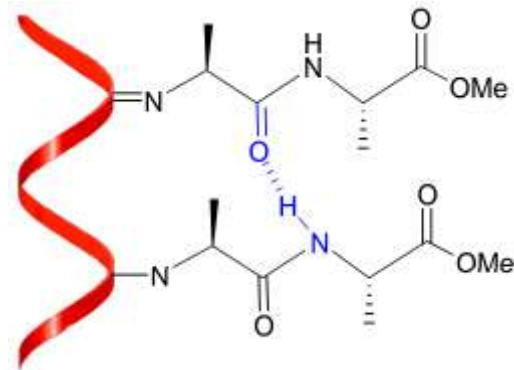
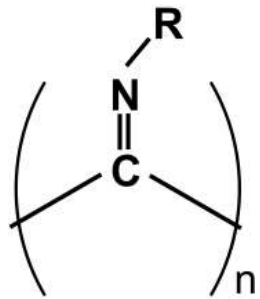
# EXAFS

- If energy of outgoing electron  $> \sim 50$  eV: spherical wave that will be scattered against electron clouds of neighbouring atoms and backscattered to emitting atom
- Interference pattern between outgoing and backscattered waves produces specific EXAFS pattern  $\rightarrow$  Information about wider environment of excited electron
- Information about number and type of neighbours, and their position (distance)

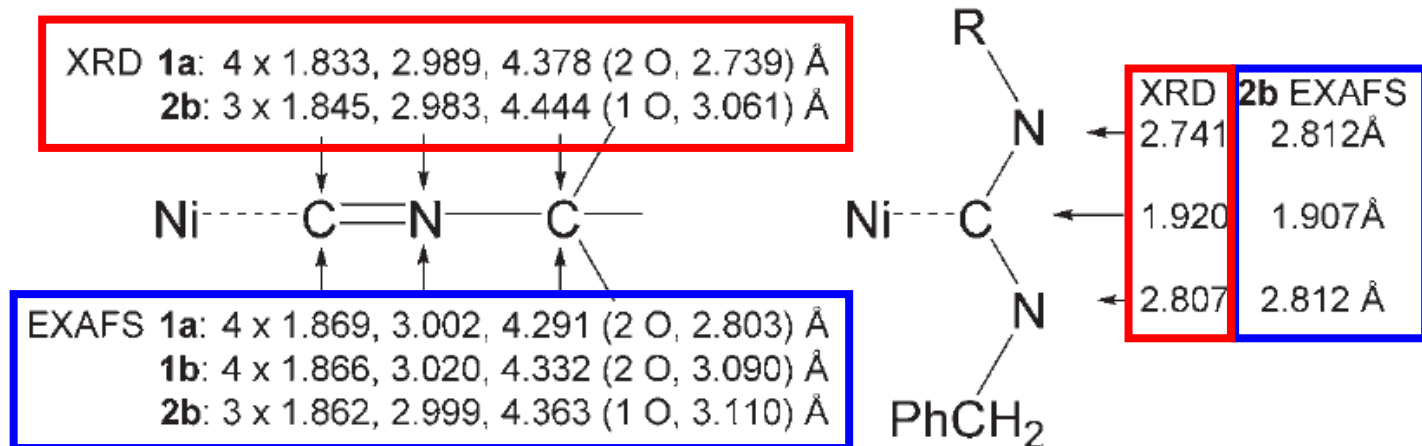
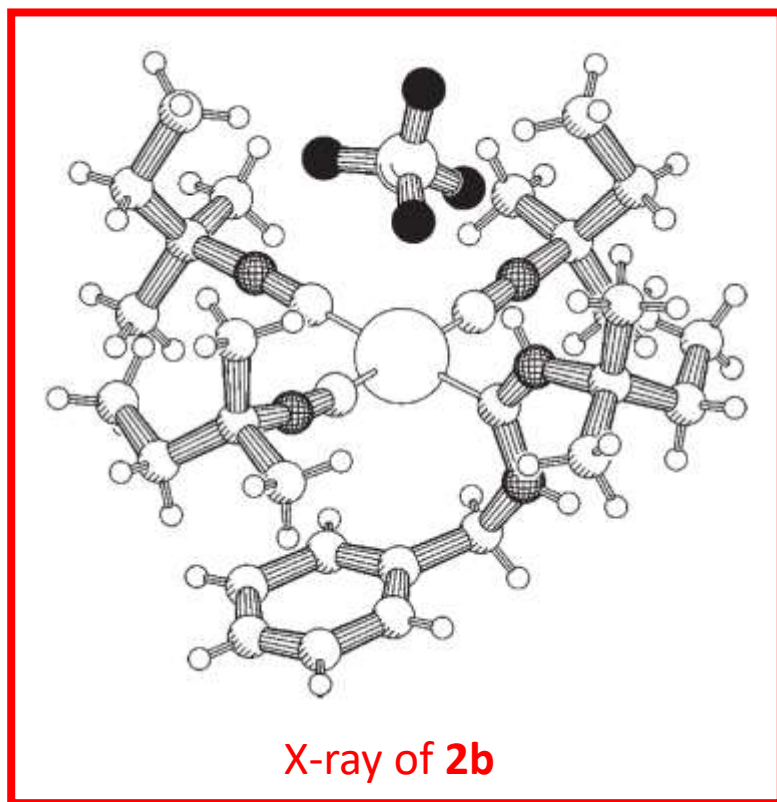
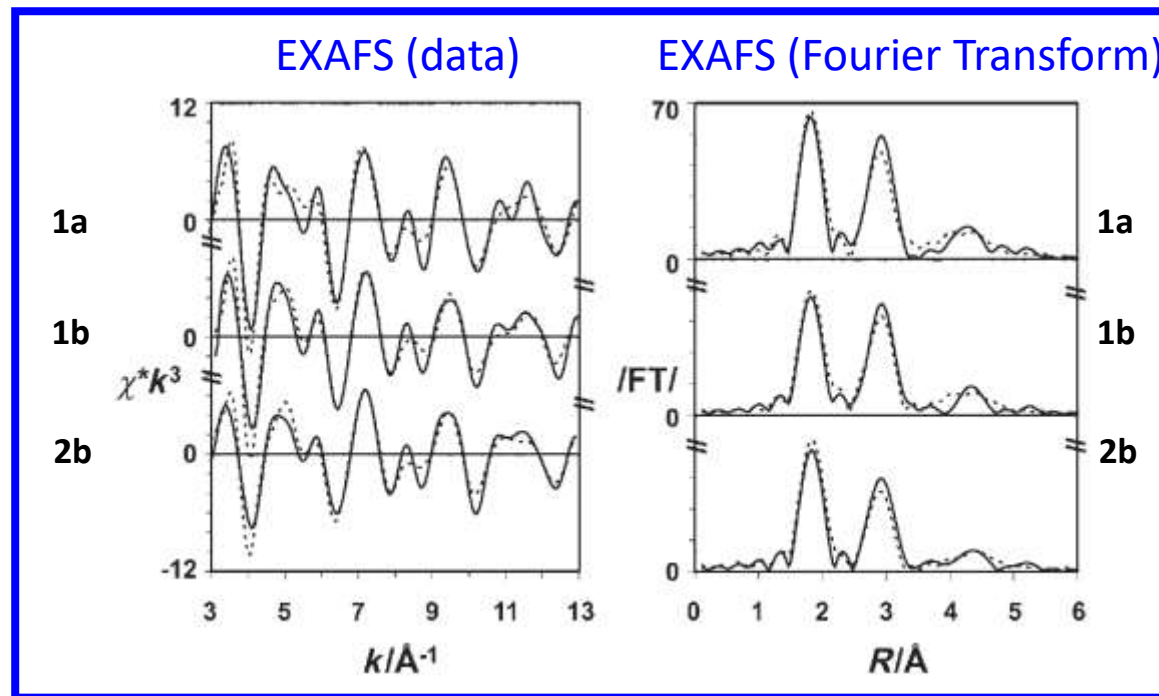
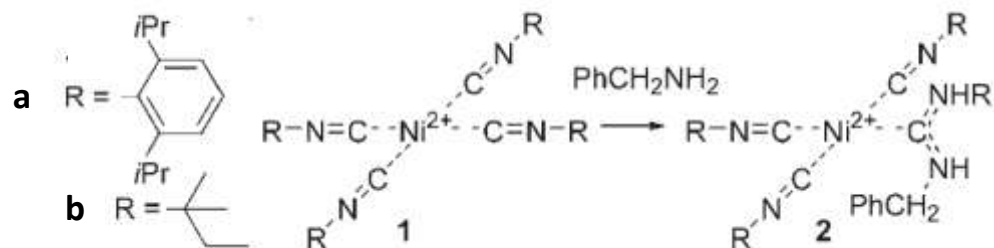


# Example of EXAFS

## Polymerization of isocyanides



# Example of EXAFS



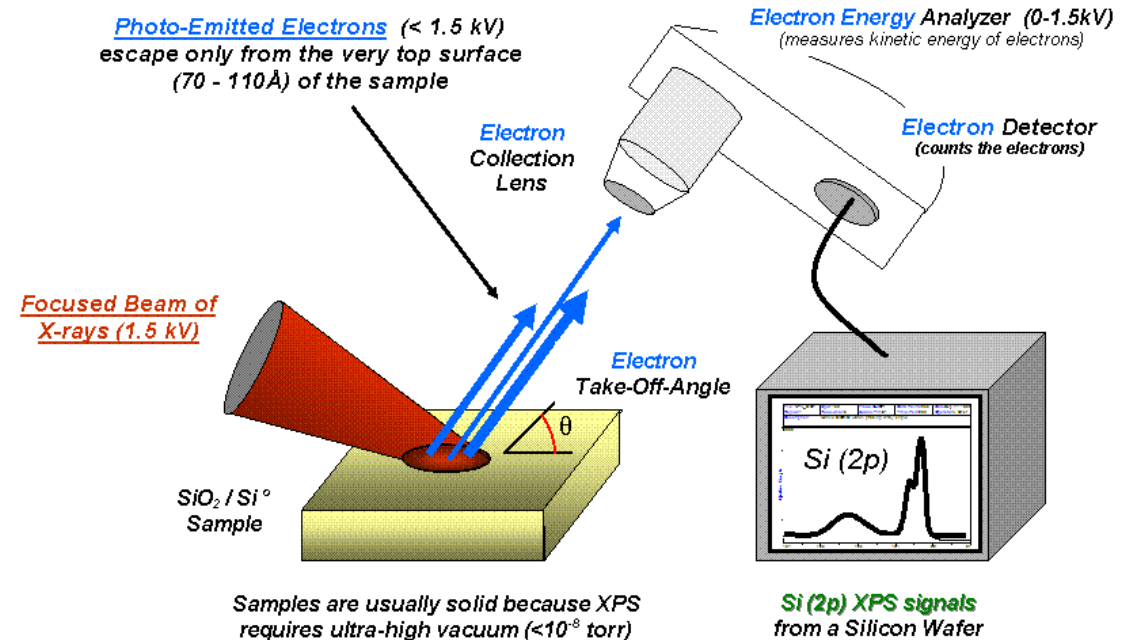
# X-ray Photoelectron Spectroscopy (XPS)

## Electromagnetic radiation with $E \sim 1.5$ keV

- Generated by interaction of high energy electrons with the surface of a (catalytic) material
- Excitation of electrons (including core) of which  $E_{\text{kinetic}}$  is measured
- Binding energy of excited electron can be determined:

$$E_{\text{binding}} = E_{\text{photon}} - (E_{\text{kinetic}} + \phi)$$

- Can provide several material properties:
  - Elemental composition (from  $E_{\text{binding}}$ )
  - Empirical formula of pure material (from intensity and surface areas of the peaks)
  - Electronic properties of elements (oxidation states)
  - Distributions (uniformity) of elements across a surface
  - Identification of contaminants on the surface



## Limitations

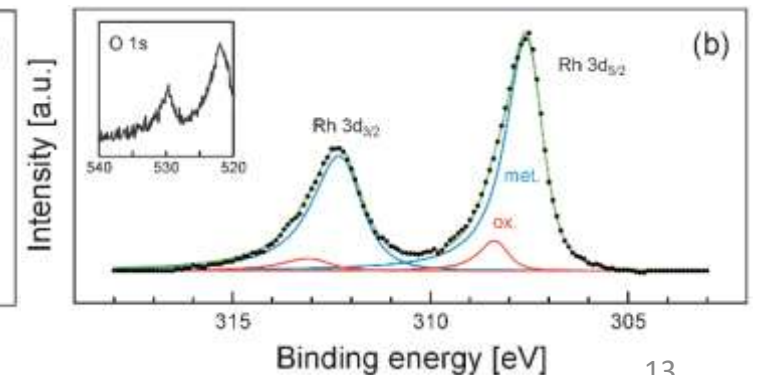
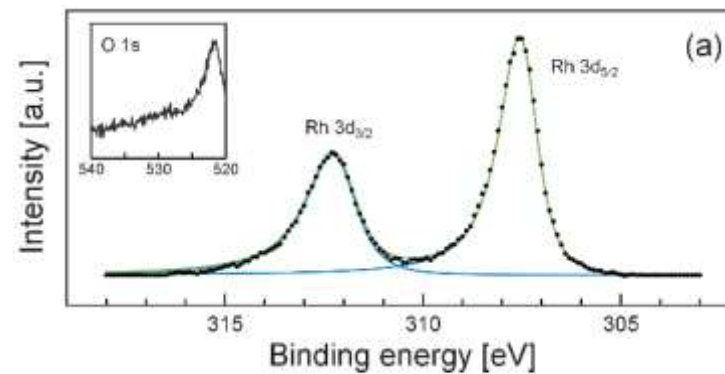
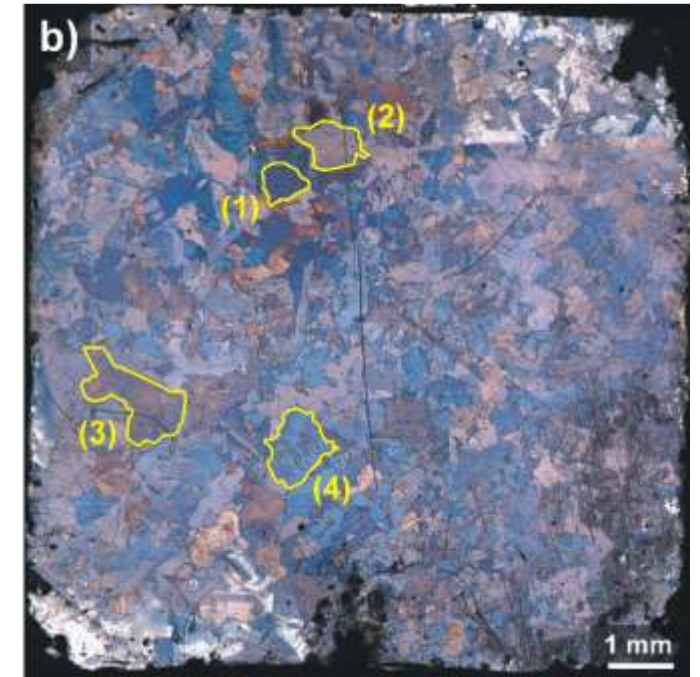
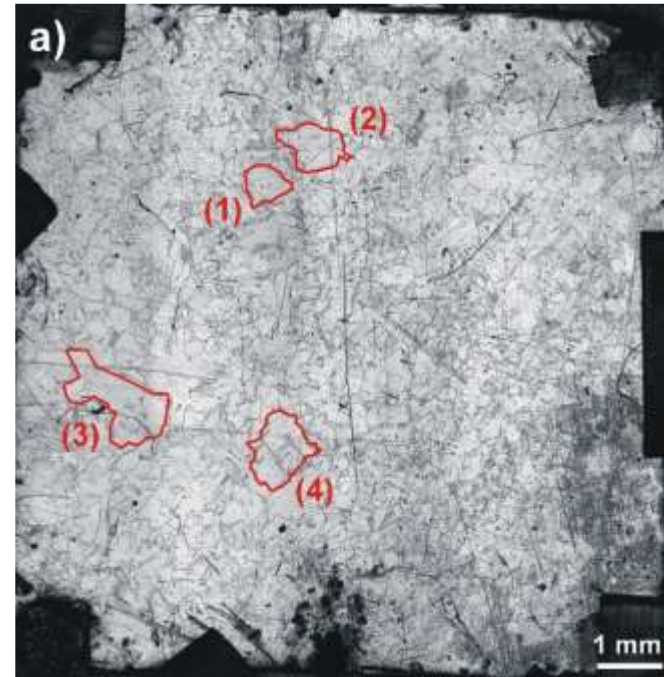
- Vacuum environment required
- Electron escape depth limited. Technique only surface-sensitive



# Example of XPS

## Oxidation of a Rh catalyst surface

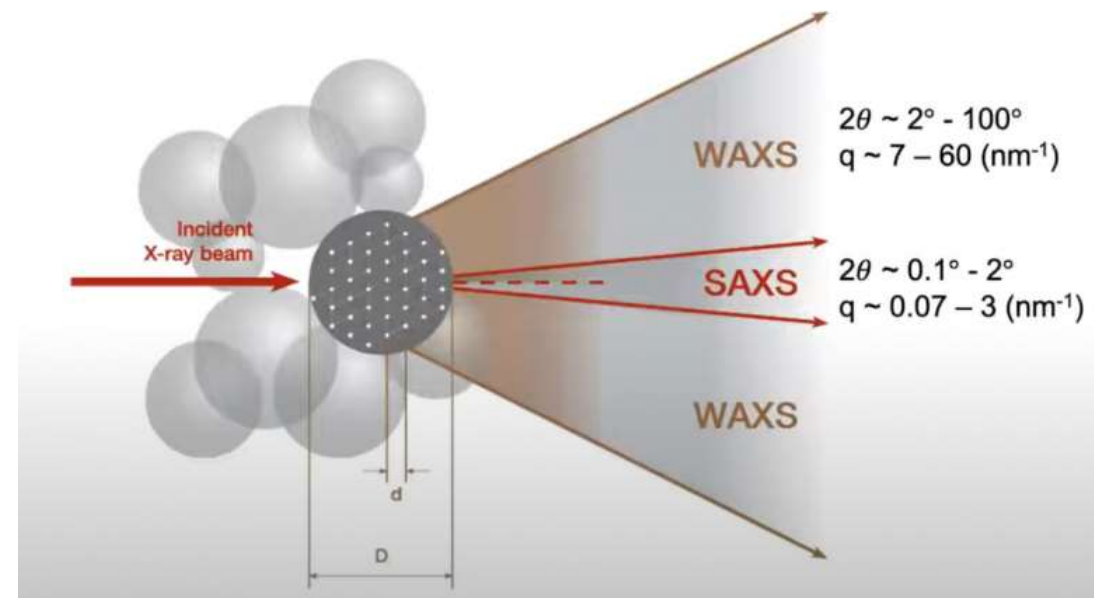
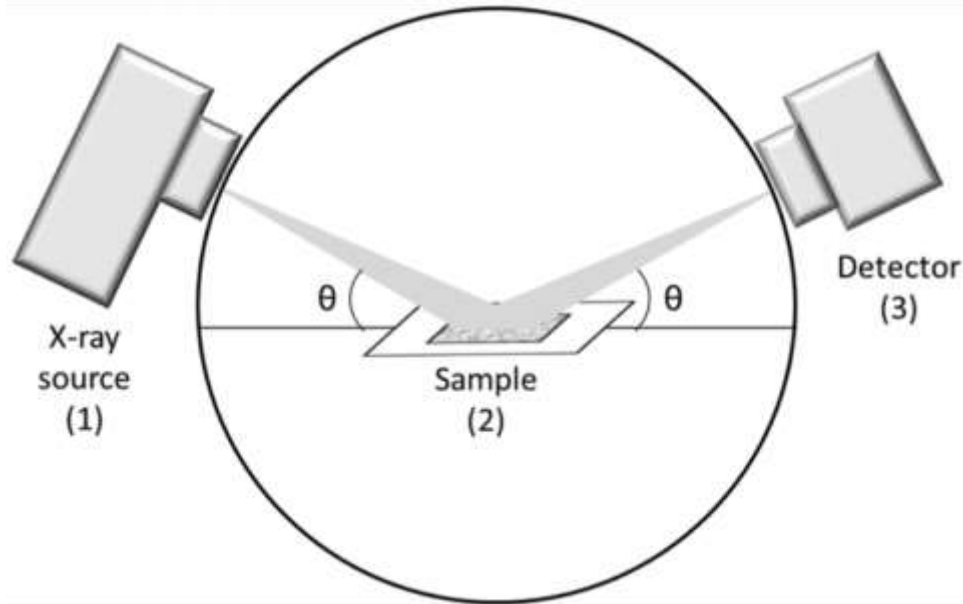
- Present in automotive exhaust catalysts
- Study on polycrystalline Rh films
- Resolution at sub-milimeter level



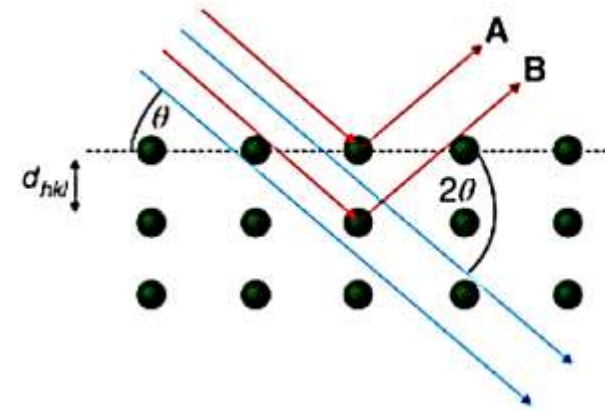
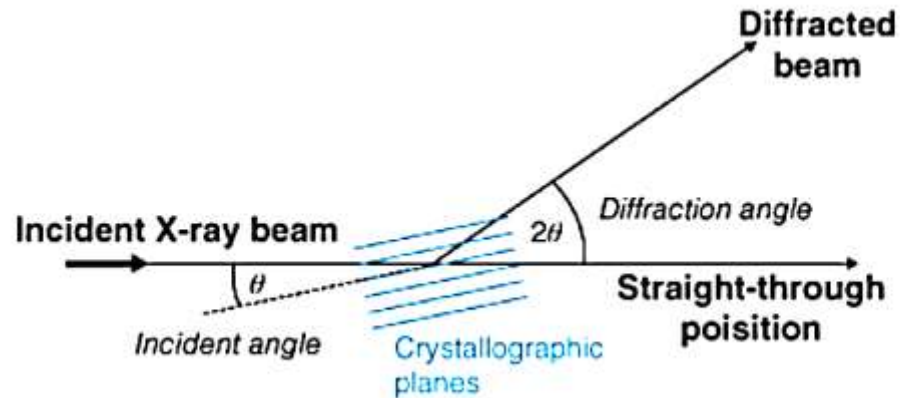
# X-ray scattering

## Incident x-rays are scattered elastically by electrons of the material

- Wide-angle X-ray scattering (**WAXS**) (or X-ray diffraction, XRD): information on the periodic crystal structure (*intramolecular* – interatomic – subnanometer level). **Atomic resolution**.
- Small-angle X-ray scattering (**SAXS**): information on the *intermolecular* level – shape and size of particles from nanometer to micrometer size. **No atomic resolution**.



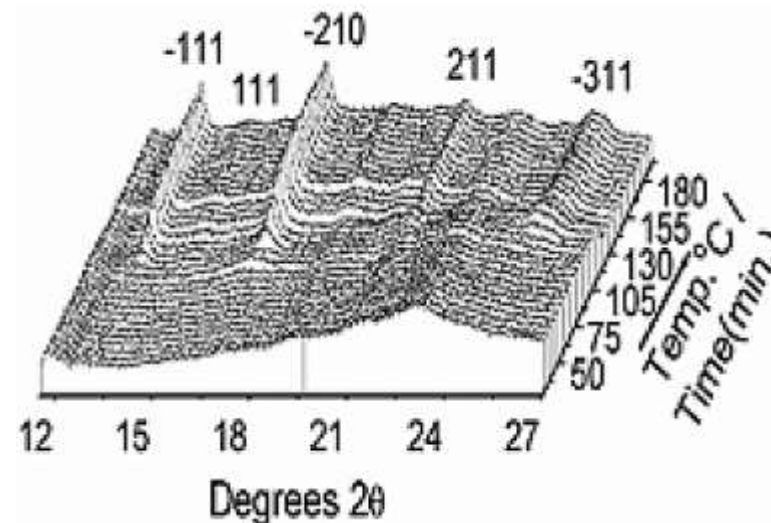
# WAXS



- Long-range order  $\rightarrow$  constructive interference of scattered waves  $\rightarrow$  Bragg's law:  $2d\sin(\vartheta) = n\lambda$
- Homogeneous/biocatalysis: single-crystal structure determination of isolated catalysts and enzymes
- Heterogeneous catalysis: *in situ* monitoring of structural transitions during catalysis and catalyst preparation

## Example

Observation of zinc-substituted microporous aluminophosphate formation at time resolution of minutes



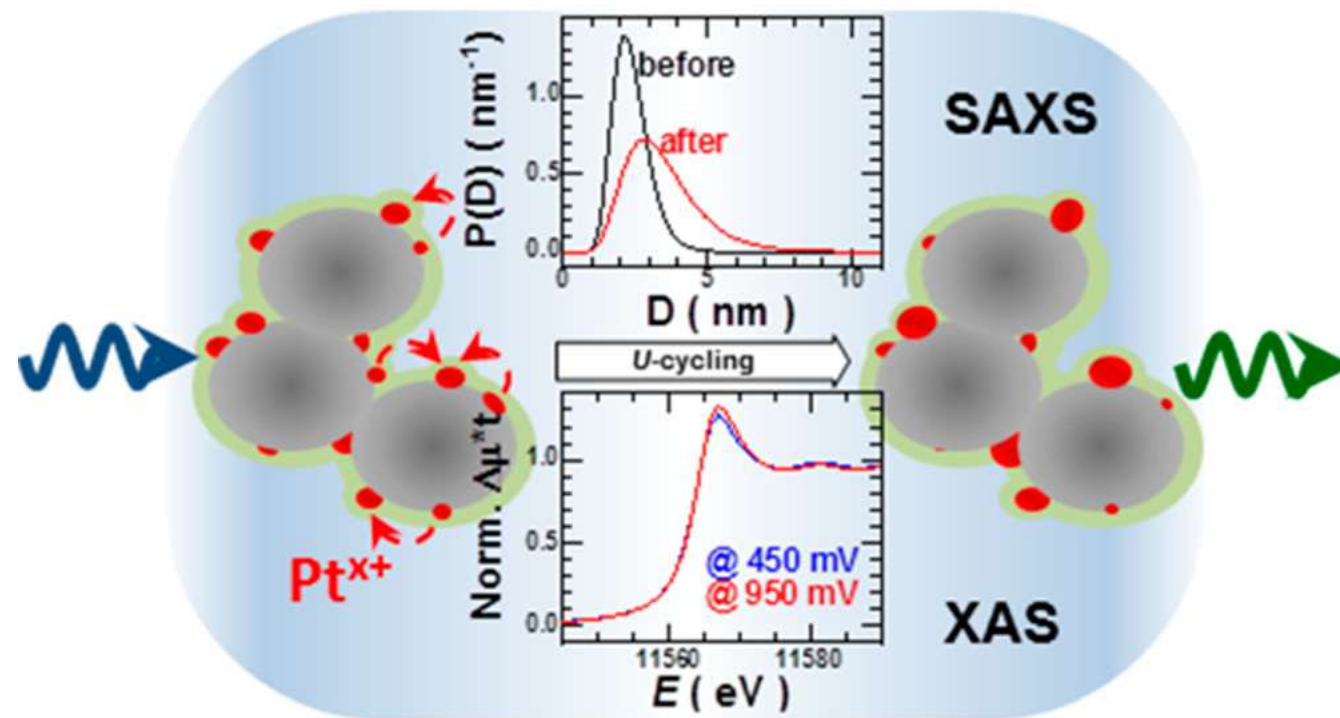
# SAXS

- Operates at much smaller angles than WAXS
- Mainly applied in polymer science. In heterogeneous catalysis for determination of particle sizes, porosity, formation mechanisms of supports and catalyst materials

## Example

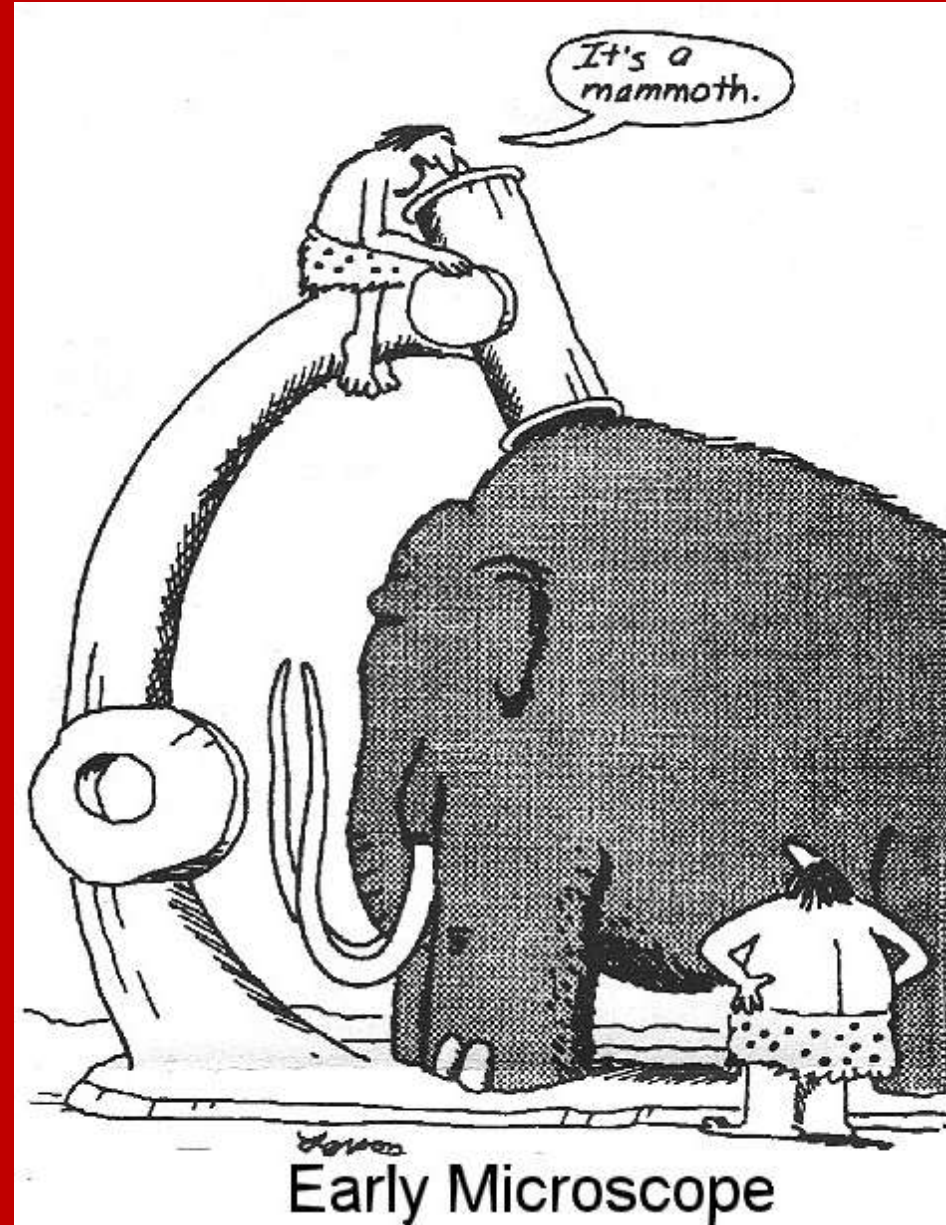
*In operando* degradation of carbon-supported Pt-nanoparticle (Pt/C) catalysts in polymer electrolyte fuel cells.

- **SAXS**: On average particles become larger
- **EXAFS**: when particles become larger, Pt-Pt distances in nanoparticles increase





# Microscopic Characterization

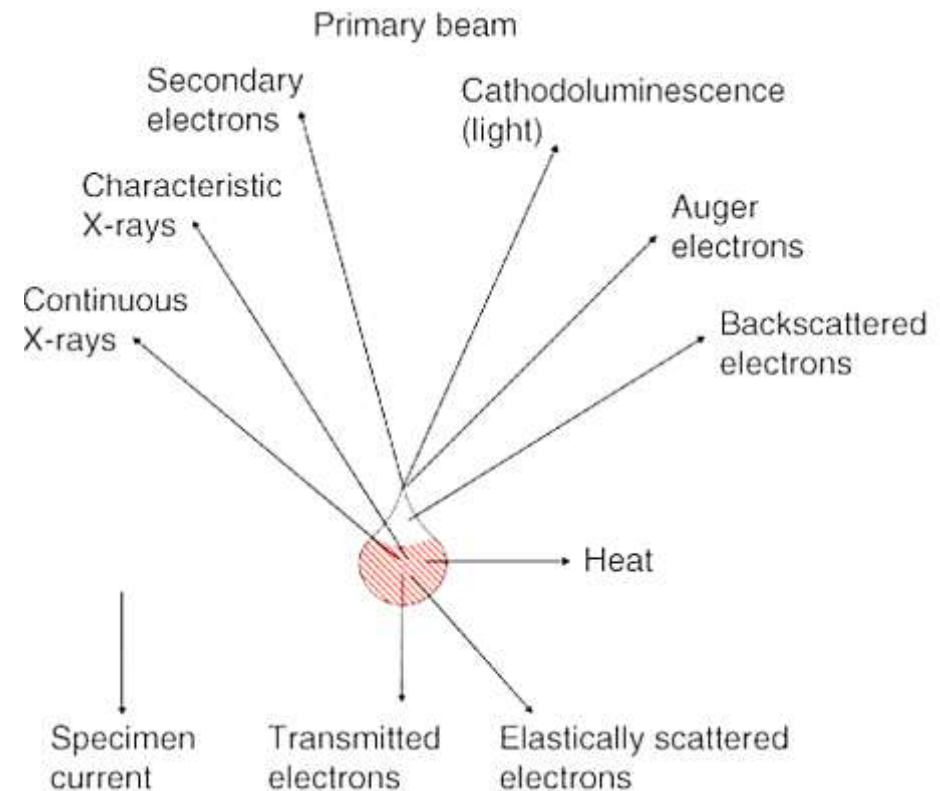


Early Microscope

# Electron microscopy

## Visualization of surface structure, homogeneity, and of materials/particles adsorbed to surfaces

- Surface exposed to primary electron beam, most often in high vacuum (but in recent years also in gases and liquids)
- Sample information may be extracted from variety of response of electron to interactions with material
- Two main types: Transmission Electron Microscopy (TEM) and Scanning Electron Microscopy (SEM)



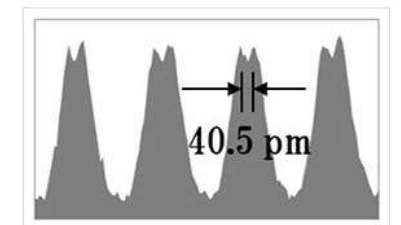
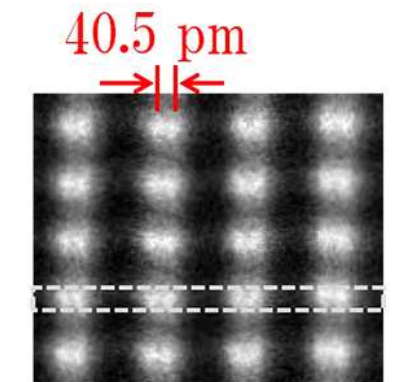
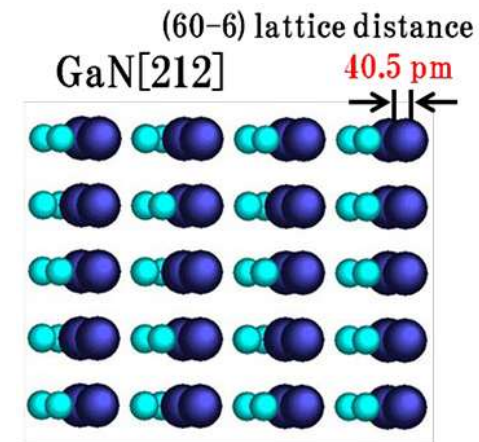
# Electron microscopy

## Transmission electron microscopy (TEM)

- Information about the bulk of the sample
- Surface is exposed to primary electron beam, most often in high vacuum
- Electrons pass through sample (which must be very thin): **absorption contrast image**
- Electrons can also be scattered by sample: **diffraction image** → information about crystalline vs. defect sites, edges, etc.
- High resolution TEM (HRTEM): atomic resolution ( $<0.5 \text{ \AA}$ ) possible.

## Limitations

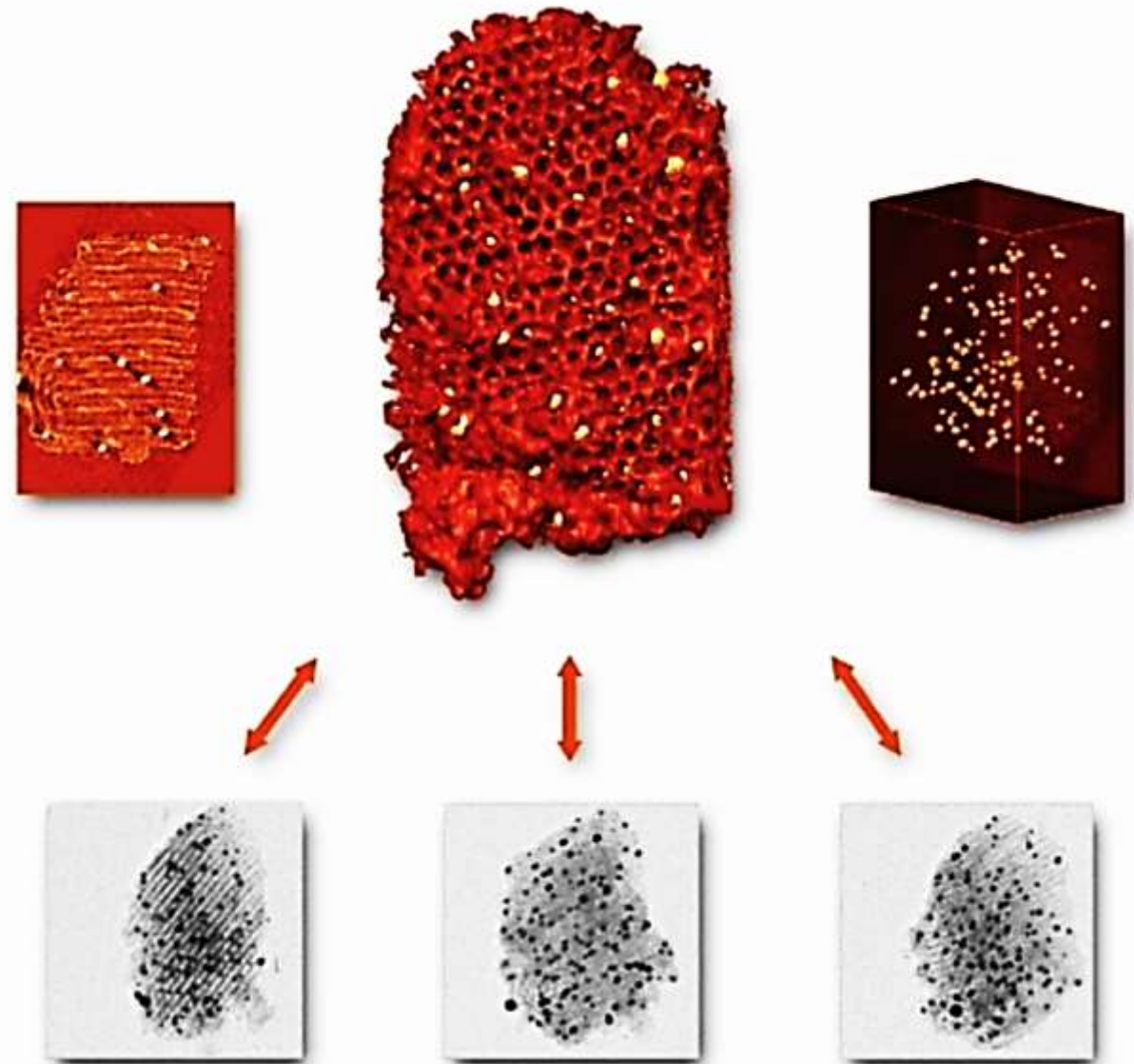
- Not always possible to get very thin samples
- Beam may change or damage the sample
- Time-consuming to obtain large overview
- Generally high vacuum needed



# Electron microscopy

## Electron tomography

- Rotation of sample inside TEM under varying angles to construct a 3D image
- Powerful tool to investigate solid catalysts (pore structures, active metal particles etc.)

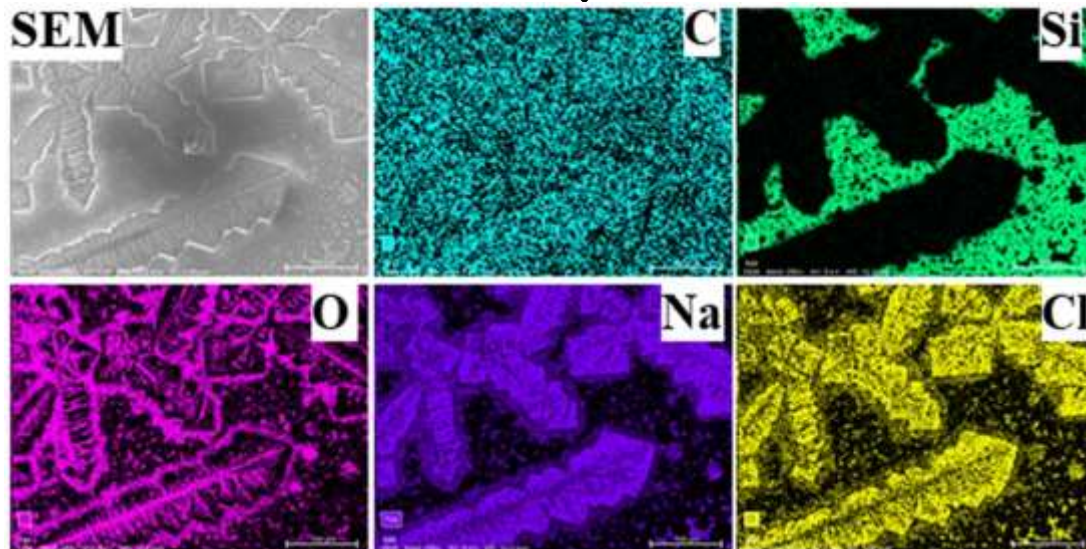
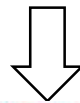




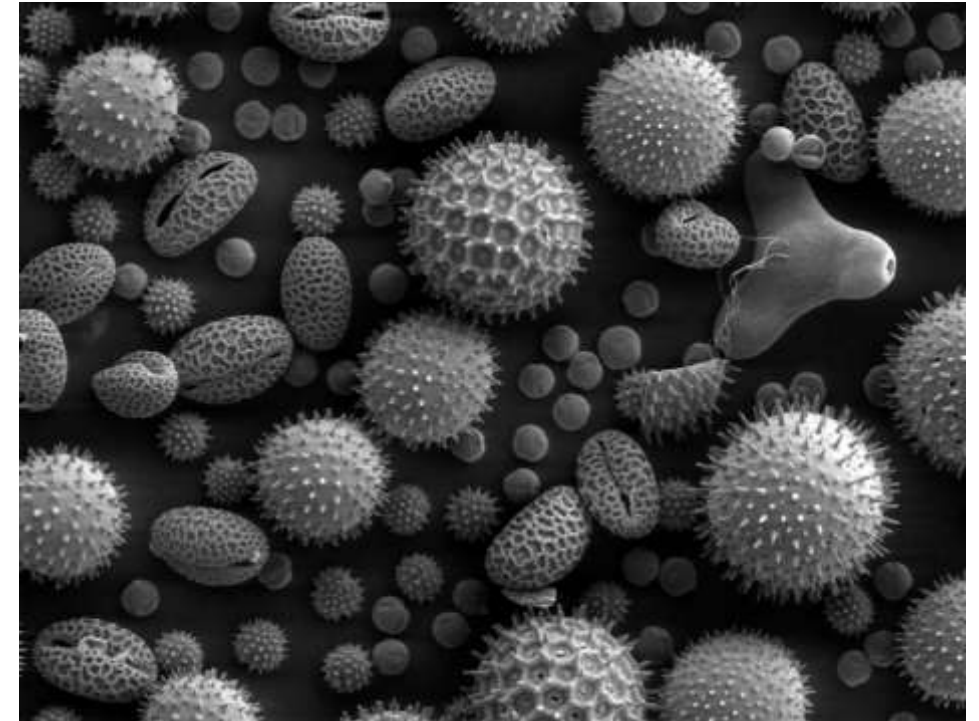
# Electron microscopy

## Scanning electron microscopy (SEM)

- Smaller electron beam is scanned (rastered) along a surface
- No transmission but emission of **secondary electrons** from the sample → information about outer surface
- Samples can be tilted so 3D-like images are obtained →
- Detection of X-rays (Energy-Dispersive X-ray (EDX) analysis) → 'elemental analysis'



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## Limitations

- Only information about top part of surface
- Scanning of a surface takes time
- High resolution more difficult than with (HR)TEM
- Generally high vacuum needed